

# APT75GN60B(G) APT75GN60S(G) 600V

Utilizing the latest Field Stop and Trench Gate technologies, these IGBT's have ultra low  $V_{CE(ON)}$  and are ideal for low frequency applications that require absolute minimum conduction loss. Easy paralleling is a result of very tight parameter distribution and a slightly positive  $V_{CE(ON)}$  temperature coefficient. A built-in gate resistor ensures extremely reliable operation, even in the event of a short circuit fault. Low gate charge simplifies gate drive design and minimizes losses.

- 600V Field Stop
- Trench Gate: Low V<sub>CE(on)</sub>
- Easy Paralleling
- 6µs Short Circuit Capability
- Intergrated Gate Resistor: Low EMI, High Reliability
  Applications: Welding, Inductive Heating, Solar Inverters, SMPS, Motor drives, UPS

#### **MAXIMUM RATINGS**

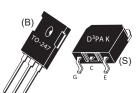
All Ratings:  $T_c = 25^{\circ}C$  unless otherwise specified.

Symbol	Parameter	APT75GN60B_S(G)	UNIT	
V <sub>CES</sub>	Collector-Emitter Voltage	600		
V <sub>GE</sub>	Gate-Emitter Voltage	±30	- Volts	
I <sub>C1</sub>	Continuous Collector Current <sup>(8)</sup> @ $T_c = 25^{\circ}C$	155		
I <sub>C2</sub>	Continuous Collector Current @ T <sub>C</sub> = 110°C	93	Amps	
I <sub>CM</sub>	Pulsed Collector Current <sup>①</sup>	225		
SSOA	Switching Safe Operating Area @ $T_{J}$ = 175°C	225A @ 600V		
P <sub>D</sub>	Total Power Dissipation	536	Watts	
$T_{J},T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 175		
Τ <sub>L</sub>	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	- °C	

#### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	ТҮР	MAX	Units
V <sub>(BR)CES</sub>	Collector-Emitter Breakdown Voltage ( $V_{GE} = 0V, I_{C} = 4mA$ )	600			- Volts
V <sub>GE(TH)</sub>	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 1mA, T_{j} = 25^{\circ}C)$	5.0	5.8	6.5	
V <sub>CE(ON)</sub>	Collector-Emitter On Voltage ( $V_{GE}$ = 15V, $I_C$ = 75A, $T_j$ = 25°C)	1.05	1.45	1.85	
CE(ON)	Collector-Emitter On Voltage ( $V_{GE}$ = 15V, $I_C$ = 75A, $T_j$ = 125°C)		1.87		
I <sub>CES</sub>	Collector Cut-off Current (V <sub>CE</sub> = 600V, V <sub>GE</sub> = 0V, T <sub>j</sub> = 25°C) <sup>(2)</sup>			25	μA
	Collector Cut-off Current (V <sub>CE</sub> = 600V, V <sub>GE</sub> = 0V, T <sub>j</sub> = 125°C) <sup>(2)</sup>				
I <sub>GES</sub>	Gate-Emitter Leakage Current (V <sub>GE</sub> = ±20V)			600	nA
R <sub>G(int)</sub>	Intergrated Gate Resistor		4		Ω

These Devices are Sensitive to Electrostatic Discharge Proper Handling Procedures Should Be Followed.





### **DYNAMIC CHARACTERISTICS**

Symbol	Characteristic	Test Conditions	MIN	ТҮР	MAX	UNIT
C <sub>ies</sub>	Input Capacitance	Capacitance		4500		pF
C <sub>oes</sub>	Output Capacitance	V <sub>GE</sub> = 0V, V <sub>CE</sub> = 25V		370		
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1 MHz		150		
V <sub>GEP</sub>	Gate-to-Emitter Plateau Voltage	Gate Charge		9.5		V
Qg	Total Gate Charge <sup>③</sup>	V <sub>GE</sub> = 15V		485		nC
Q <sub>ge</sub>	Gate-Emitter Charge	V <sub>CE</sub> = 300V		30		
Q <sub>gc</sub>	Gate-Collector ("Miller") Charge	I <sub>C</sub> = 75A		270		
SSOA	Switching Safe Operating Area	$T_J = 175^{\circ}C, R_G = 4.3\Omega^{(2)}, V_{GE} = 15V, L = 100\mu H, V_{CE} = 600V$	225			A
SCSOA	Short Circuit Safe Operating Area	$V_{CC} = 600V, V_{GE} = 15V,$ $T_{J} = 125^{\circ}C, R_{G} = 4.3\Omega^{7}$	6			μs
t <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (25°C)		47		
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 400V		48		ne
t <sub>d(off)</sub>	Turn-off Delay Time	V <sub>GE</sub> = 15V		385		- ns
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 75A		38		]
E <sub>on1</sub>	Turn-on Switching Energy <sup>④</sup>	$R_{G} = 1.0\Omega^{7}$		2500		
E <sub>on2</sub>	Turn-on Switching Energy (Diode) <sup>⑤</sup>	T <sub>J</sub> = +25°C		3725		μJ
E <sub>off</sub>	Turn-off Switching Energy <sup>6</sup>			2140		1
t <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (125°C)		47		- ns
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 400V		48		
t <sub>d(off)</sub>	Turn-off Delay Time	V <sub>GE</sub> = 15V		430		
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 75A		55		
E <sub>on1</sub>	Turn-on Switching Energy <sup>④</sup>	$R_{G} = 1.0\Omega^{\textcircled{O}}$		2600		μJ
E <sub>on2</sub>	Turn-on Switching Energy (Diode) <sup>⑤</sup>	T <sub>J</sub> = +125°C		4525		
E <sub>off</sub>	Turn-off Switching Energy <sup>6</sup>			2585		

## THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
R <sub>θJC</sub>	Junction to Case (IGBT)			.28	°C/W
R <sub>θJC</sub>	Junction to Case (DIODE)			N/A	
W <sub>T</sub>	Package Weight		5.9		gm

(1) Repetitive Rating: Pulse width limited by maximum junction temperature.

2 For Combi devices,  $\textbf{I}_{ces}$  includes both IGBT and FRED leakages

③ See MIL-STD-750 Method 3471.

(4)  $E_{on1}$  is the clamped inductive turn-on energy of the IGBT only, without the effect of a commutating diode reverse recovery current adding to the IGBT turn-on loss. Tested in inductive switching test circuit shown in figure 21, but with a Silicon Carbide diode.

(5) E<sub>on2</sub> is the clamped inductive turn-on energy that includes a commutating diode reverse recovery current in the IGBT turn-on switching loss. (See Figures 21, 22.)

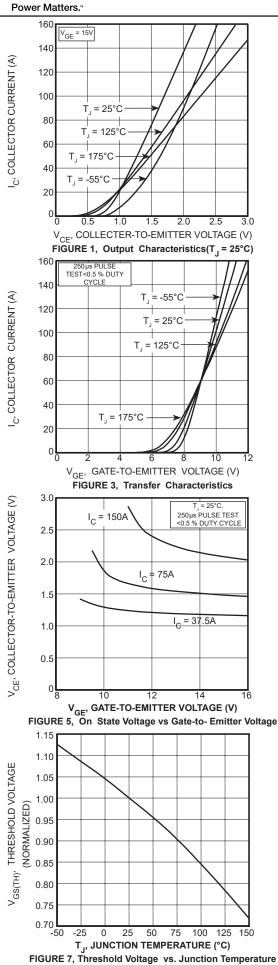
(6) E<sub>off</sub> is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1. (See Figures 21, 23.)

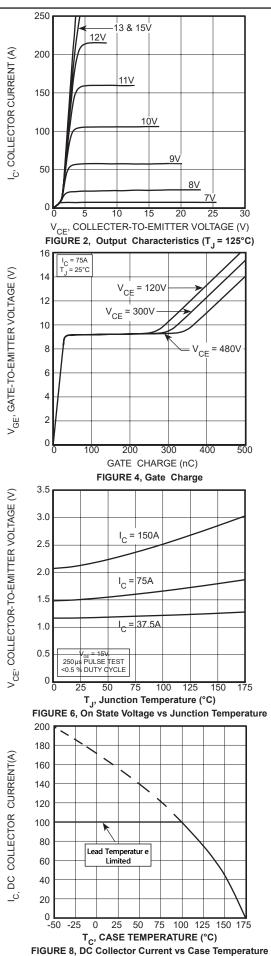
 $\bigcirc$  R<sub>G</sub> is external gate resistance, not including R<sub>G(int)</sub> nor gate driver impedance. (MIC4452)

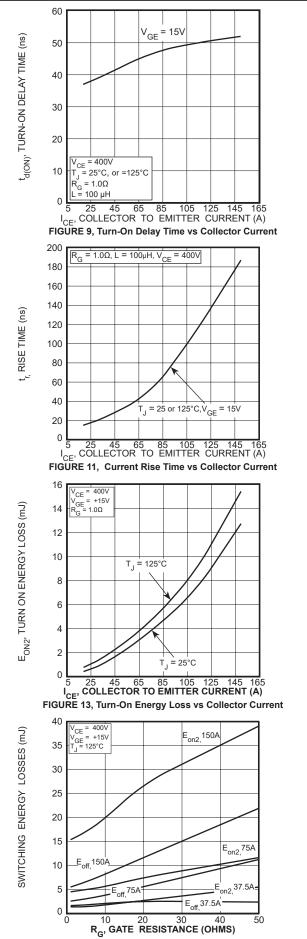
8 Continuous current limited by package pin temperature to 100A.

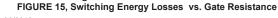
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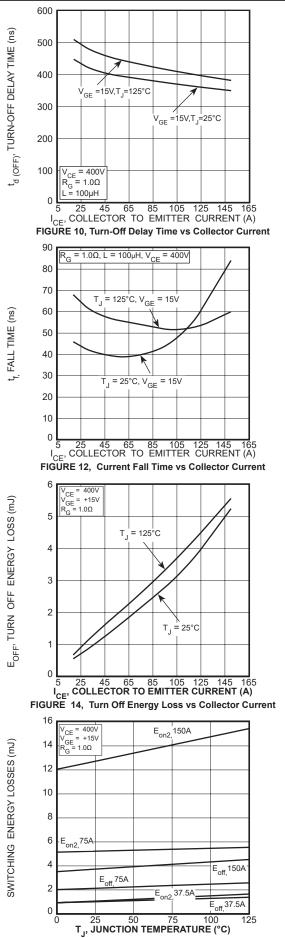
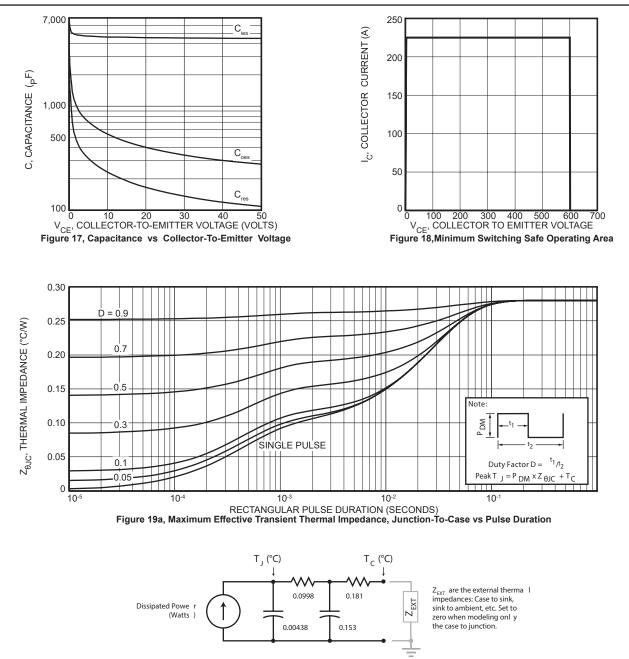
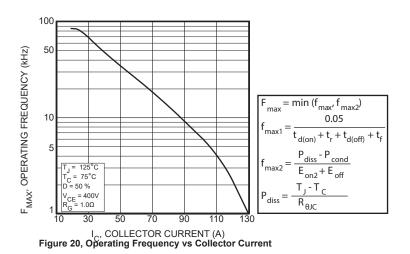


FIGURE 16, Switching Energy Losses vs Junction Temperature









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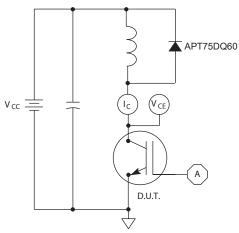


Figure 21, Inductive Switching Test Circuit

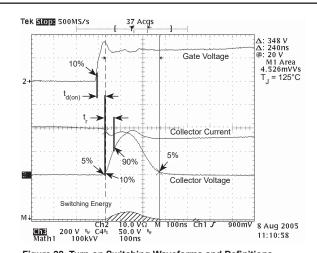


Figure 22, Turn-on Switching Waveforms and Definitions

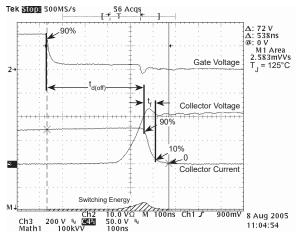
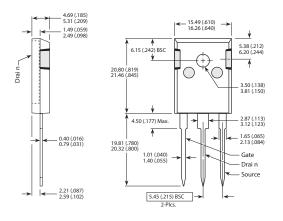
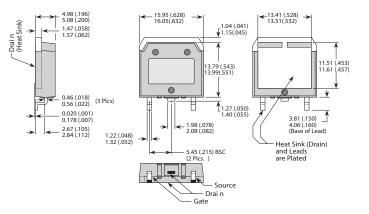


Figure 23, Turn-off Switching Waveforms and Definitions

TO-247 (B) Package Outline



#### D<sup>3</sup>PAK (S) Package Outline



**Dimensions in Millimeters (Inches)** 

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